

Lattice Series

High-Power X-ray

INTRODUCTION

"Crystal Clear Precision"

The **Lattice Series** redefines benchtop X-ray diffraction by combining high-power performance with compact design. Equipped with a powerful 600 W (**Lattice Mini**) or 1600 W X-ray source and a high-efficiency, direct-read 2D photon detector, the Lattice Series delivers exceptional data intensity and accuracy—making it ideal for demanding analytical environments.

Available in three configurations—**Lattice Mini**, **Lattice Basic**, and **Lattice Pro**—this series accommodates a wide range of technical and budgetary needs, from simple phase identification to complex in-situ studies. All models offer excellent signal-to-noise ratio and fast scan speeds, providing lab-grade data from a desktop system.

Whether you're analyzing complex powders, crystalline materials, or conducting high-throughput measurements, the Lattice Series provides lab-grade results with speed, power, and precision—all in a desktop footprint.

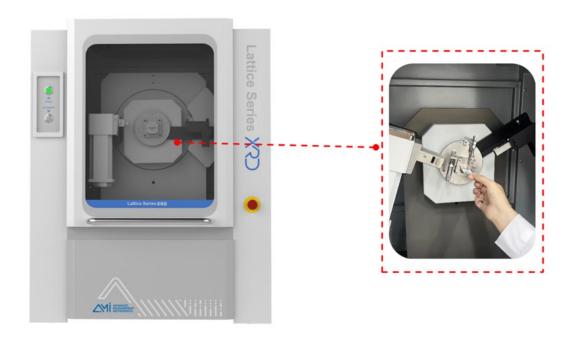


Figure 1 Lattice Series Instrument



MODEL SERIES

The Lattice Mini is the ideal entry point for high-quality X-ray diffraction. Designed for users who need reliable phase identification and material characterization in a truly space-saving format, the Lattice Mini delivers powerful performance in a compact, affordable package.

Ideal for:

- · University and teaching laboratories
- Small research groups
- Routine QA/QC in ceramics, metals, and minerals
- Rapid phase screening and basic material studies

The Lattice Basic is designed for laboratories that require dependable, high-throughput diffraction without the complexity of advanced custom configurations. With high angular resolution and a direct-read 2D photon detector, the Lattice Basic delivers fast, accurate results across a wide range of powder samples. It's an excellent choice for users who prioritize precision, speed, and reliability—at an efficient price point.

Ideal for:

- QA/QC labs
- Materials characterization
- · Educational and institutional research
- · Cement, ceramics, metals, and pharmaceuticals

The Lattice Pro is built for the most demanding applications. Featuring Theta–Theta geometry for enhanced sample stability and accessory support, it enables precise, high-performance analysis for advanced materials, coatings, and stress testing.

Ideal for:

- Advanced R&D environments
- Dynamic experiments
- Residual stress analysis
- Film, coating, and thin-layer characterization
- Battery and energy materials research



KEY FEATURES

• High-Power X-ray Source

Choose between 600 W or 1600 W configurations for high-intensity data collection and rapid scanning.

• 2D Photon Direct-Read Detector

A 256×256 pixel array captures sharp, high-resolution diffraction patterns with an excellent signal-to-noise ratio.

• Exceptional Angular Accuracy

Achieve step sizes as small as $\pm 0.01^{\circ}$ 20 and ensure a consistent peak matching with standard reference materials.

• Flexible Goniometer Options

Theta-2Theta geometry for standard analysis (Mini & Basic) or Theta-Theta for enhanced sample stability (Pro).

• Fast, Reliable Scanning

Obtain full-spectrum data in minutes—ideal for routine QA and high-throughput labs.

• Compact Benchtop Design

Fits seamlessly into modern lab environments without sacrificing performance or requiring floor space.

• Expandable Functionality (Lattice Pro)

Supports advanced modules for residual stress testing, high-temperature stages, in-situ battery studies, and thin film analysis.

• User-Friendly Operation

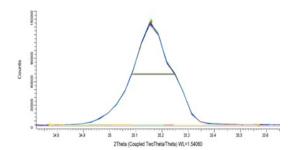
Intuitive software and streamlined hardware design simplify training and daily use.

PERFORMANCE EXAMPLES

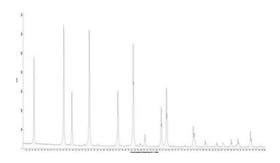
The Lattice Series is not only powerful on paper—it delivers real-world results across a wide range of materials and industries. From standard reference materials to advanced composites, its high data intensity, precision, and repeatability ensure confidence in every scan. Whether you're measuring graphitization, stress, crystallinity, or phase content, the Lattice Series offers reliable performance backed by quantitative results.

Miller Indices	Theoretical Peak	Measured Peak	Difference	
Miller muices	Position	Position	Difference	
012	25.579	25.577	0.0020	
104	35.153	35.15	0.0030	
116	57.497	57.497	0.0000	
1010	76.871	76.872	0.0010	
0210	88.997	88.996	-0.0010	
0114	116.612	116.61	-0.0020	

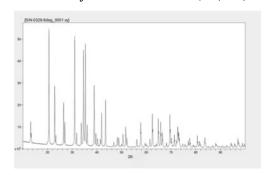
Comparison of Theoretical Peak Positions and Measured Peak Positions for Corundum Standard Sample



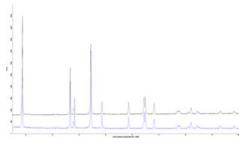
 ${\it Instrument \, Repeatability \, Measurement}$



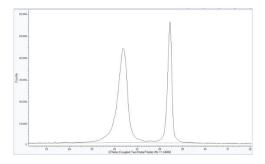
Test Data for Corundum Powder (10°/min)



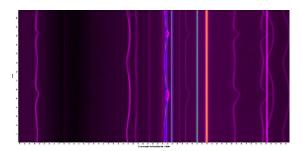
Measurement Spectrum for Silicon Nitride Ceramic



XRD Spectrum of Ternary Materials Black represents regular measurement mode data, and blue represents fluorescence-free mode data.



Graphitization Degree Measurement



Reflective In-Situ Battery Measurements



TECHNICAL PARAMETERS

Model	Lattice Mini	Lattice Basic	Lattice Pro		
X-ray tube	600 W	1600 W			
X-ray tube target material	Standard Cu target, Co target is optional				
Theodolite	radius of the theodolite is	Theta / 2theta geometry, the radius of the theodolite is 170 mm	Theta / theta geometry, the radius of the theodolite is 170 mm		
Maximum scanning range	-3 - 156°				
Theta Minimum step size	±0.01°				
Detector	Photon direct-read two-dimensional array detector				
Detector energy resolution	0.2				
Volume and Weight	L 25.6 in (650 mm) × W 19.7 in (500 mm) × H 15.8 in (400 mm), 132 lbs (60 kg)	L 35.5 in (900 mm) × W 26.8 in (680 mm) × H 21.7 in (500 mm), 220 lbs (100 kg)			
Sample stage	Standard chip stage				
Options	N/A	Five-bit injector; In situ battery test accessories;	Five-bit injector; In situ battery test accessories; High temperature sample station: can be customized according to customer requirements, e.g., RT-600°C/RT- 1000°C; Residual stress measuring fixture (can be customized); Film sample stage: Size: 2.4 in (60mm) × 2.4 in (60mm) (can be customized)		